

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Wongsenakhum et al.

Attorney Docket No.: NOVLP096/NVLS-2902

Application No.: 10/815,560

Examiner: Estrada, M.

Filed: March 31, 2004

Group: 2823

Title: METHOD OF FORMING LOW-

RESISTIVITY TUNGSTEN

INTERCONNECTS

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on October 12, 2005 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 228 18-1450.

Signed:

Tara Hayden

INFORMATION DISCLOSURE STATEMENT BEFORE FINAL ACTION OR NOTICE OF ALLOWANCE (37 CFR §§ 1.56 AND 1.97(c))

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, a copy of which is attached, may be material to examination of the above-identified patent application. Applicants submit this reference in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make this citation of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that this reference indeed constitutes prior art.

This Information Disclosure Statement is being filed after the mailing date of the first Office Action on the merits, or after three months of the filing date of this application, whichever event occurred last, but it is believed before the mailing date of either: (i) a final action under §1.113 or (ii) a notice of allowance under §1.311, whichever occurs first.

10/19/2005 RFEKADU1 00000009 10815560

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| Accompanying this Information Disclosure State          | ement is                                 |
|---|--|
| a statement as specified in 37 CFR                      | 1.97(e); or                              |
| the fee set forth in 37 CFR 1.17(p).                    |  |
| If fees are due, enclosed is our Check No.              | for \$180.00 in payment of the           |
| Information Disclosure Statement Fee. If it is determin | ed that any additional fees are due, the |
| Commissioner is hereby authorized to charge such fees   | to Deposit Account 500388 (Order No      |
| NOVLP096).  | ,  |
|   |  |

Respectfully submitted,
BEYER WEAVER & THOMAS, LLP

Denise S. Bergin Registration No. 50,581

P.O. Box 70250 Oakland, CA 94612-0250 Atty Docket No. Application No.:
NOVLP096/NVLS-2902 10/815,560

Information Disclosure
Statement By Applicant
Wongsenakhum et al.
Filing Date
Group
March 31, 2004 2823

**U.S. Patent Documents** 

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Foreign Patent or Published Foreign Patent Application

|          |     |            |             | 8             |       |       |       |        |
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| Examiner |     | Document   | Publication | Country or    |       | Sub-  | Trans | lation |
| Initial  | No. | No.        | Date        | Patent Office | Class | class | Yes   | No     |
|          | B1  | WO01/27147 | 04/19/01    | WIPO          |       |       | X     |        |

## Other Documents

| Examiner |     |   |  |  |
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|          | C1  | U.S. Office Action mailed July 17, 2002, from U.S. Application No. 09/975,074     |  |  |
|          |     | [Atty Dkt. NOVLP033/NVLS-000498].   |  |  |
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| Examiner |     | Date Considered   |  |  |
|          |     |   |  |  |

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

| Form 1449 (Modified)              | Atty Docket No.<br>NOVLP096/NVLS-2902 | Application No.: 10/815,560 |  |
|-----------------------------------|---------------------------------------|-----------------------------|--|
| Information Disclosure            | Applicant:                            |                             |  |
| Statement By Applicant            | Wongsenakhum et al.                   |                             |  |
|                                   | Filing Date                           | Group                       |  |
| (Use Several Sheets if Necessary) | March 31, 2004                        | 2823                        |  |

## **Other Documents**

| Examiner |     |  |
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|          |     | 10/649,351, pages 1-40. [NOVLP033X1/NVLS-000498X1]                                     |
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| Examiner |     | Date Considered  |

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.